



## Introduction

The Keysight Technologies, Inc. 81600B Tunable Laser Source Family offers the full wavelength range from 1260 nm to 1640 nm with no wavelength gaps. This provides test instrumentation with maximum flexibility.

Investing in the Keysight 81600B Tunable Laser Source Family can realize the cost efficiency and performance required to test components for coarse and dense wavelength division multiplexing (CWDM, DWDM) and passive optical networks (PON).

### Keysight 81600B Tunable Laser Source Family

The Keysight 81600B Tunable Laser Source Family consists of seven modules that fit into the bottom slot of the Keysight 8164B Lightwave Solution Mainframe.

The 81600B Option 200 and 201 Allband Tunable Laser Sources are the flagship models, featuring the widest tuning range of 200 nm, respectively 185 nm, with a single laser and a 70 dB/nm signal-to-source spontaneous emission ratio (signal-to-SSE ratio). The excellent low-SSE performance typically allows crosstalk measurements of better than 70 dB/nm signal-to-source spontaneous emission ratio (signal-to-SSE ratio). This and the high signal power permit measurements of wavelength isolation to 100 dB, most often limited by power meter sensitivity.

# Full wavelength range from 1260 nm to 1640 nm

The Keysight 81600B Tunable Laser Source Family offers the full wavelength range from 1260 nm to 1640 nm with no wavelength gaps. The N7700A software suite has a measurement engine for IL and PDL that can combine the sweeps of up to 3 tunable laser wavelength ranges. Such a setup can be used for testing CWDM multiplexers.

# O-band models for the latest applications

The 81600B options 130 and 132 cover the wavelength range from 1260 nm to 1375 nm for an important set of applications. With the PMF output fiber, these are a good match for testing and developing components with silicon photonics technology. And especially with low-SSE, the Option 130 is the best tool for testing wavelength filters for LR4 components.

### Integrated solutions for swept-wavelength spectral measurements

The 81600B is supported with the N7700A software suite for spectral measurements of insertion loss, polarization dependent loss and dispersion in combination with power meters and polarization instruments. These provide optimal sweptwavelength accuracy dynamic range. See the N7700A brochure for details.

# Low SSE output port for high dynamic range

The 81600B option 201, 200, 160, 150, 140 and 130 Tunable Laser Sources are equipped with two optical outputs.

The low-SSE output port of the dual-output models delivers a signal with ultra-low source spontaneous emission. It enables accurate crosstalk measurement of DWDM, CWDM and PON wavelength filtering components by producing light only at the desired wavelength.

The second output port provides high optical power, adjustable over a power range of more than 60 dB via a built-in optical attenuator.

### High power output for multipurpose component tests

The Keysight 81600B Options 142 and 132 provide one output port with high stimulus power for applications where the SSE level is not critical.

The 81600B Option 142 can also be equipped with a built-in optical attenuator, so providing an adjustable power range of 60 dB.

# Built-in wavelength meter for optimum tuning precision

The Keysight 81600B Tunable Laser Source Family includes a built-in real time wavelength meter which realizes an absolute wavelength accuracy of  $\pm$  10 pm (typical  $\pm$  3.6 pm) as a standalone instrument.

# Specified performance in the continuous sweep mode

As manufacturing yield expectations becomes more and more stringent, it is important that all instruments deliver optimum performance under all measurement conditions.

The Keysight 81600B Tunable Laser Source Family can sweep as fast as 80 nm/s with specified accuracy during the sweep.

### Realize the cost efficiency and performance benefits in WDM component tests

The testing of optical filters is based on a generic principle, namely the stimulus-response test. The stateof-the-art approach is a wavelengthresolved stimulus-response measurement utilizing a tunable laser source that is capable of fast and precise sweeps across the entire wavelength range, and optical power meters.

For DWDM components, high wavelength accuracy and dynamic range are critical. For CWDM and PON components, a wide wavelength range, dynamic range and tight costing are key targets. If the investment in the test solution can be shared among many different type of filters, the contribution to each individual filter is minimized. In this way, cost targets for CWDM and PON components can be met without sacrificing accuracy.

Investing in the Keysight 81600B Tunable Laser Source Family can realize both the cost efficiency and performance benefits required.

### Polarization maintaining fiber for the test of integrated optical devices

The 81600B Tunable Laser Source Family is ideal for characterizing integrated optical devices. Its PMF output ports provide a well-defined state of polarization to ensure constant measurement conditions for waveguide devices. A PMF cable easily connects to an external optical modulator.

# 81600B Option 201 All-Band Tunable Laser, 1455 nm to 1640 nm, Low SSE 81600B Option 200 All-Band Tunable Laser, 1440 nm to 1640 nm, Low SSE

Keysight 81600B Option 201, 200				
Wavelength range	1455 nm to 1640 nm (81600B Option 201) 1440 nm to 1640 nm (81600B Option 200)			
Wavelength resolution	0.1 pm, 12.5 MHz at 1550 nm			
Mode-hop free tunability	Full wavelength range; see page 10 for conditions to assure mode-hop free cor			-hop free continuous
	sweeps			
Maximum sweep speed	80 nm/s			
	Stepped mode	Continuous sw	eep mode (typical)	
		At 5 nm/s	At 40 nm/s	At 80 nm/s
Absolute wavelength accuracy <sup>1</sup>	± 10 pm, typical ± 3.6 pm	± 4.0 pm	± 4.6 pm	± 6.1 pm
Relative wavelength accuracy <sup>1</sup>	± 5 pm, typical ± 2 pm	± 2.4 pm	± 2.8 pm	± 4.0 pm
Wavelength repeatability	± 0.8 pm, typical ± 0.5 pm	± 0.3 pm	± 0.4 pm	± 0.7 pm
Wavelength stability <sup>4</sup> (typical)	≤±1 pm, 24 hours			
Linewidth (typical), coherence control off	100 kHz			
Effective linewidth (typical), coherence	> 50 MHz (1475 nm to 1625	5 nm, at max. cons	tant output power)	
control on				
Maximum output power (continuous power	Output 1 (low SSE)		Output 2 (high power)	
during sweep)	≥ +3 dBm peak (typical)		≥ +9 dBm peak (typical)	
	≥ +2 dBm (1520 nm to 1610 nm)		≥ +8 dBm (1520 nm to1610 nm)	
	≥ –2 dBm (1475 nm to 1625 nm)		≥ +4 dBm (1475 nm to 1625 nm)	
	≥ –7 dBm ⁵		≥ −1 dBm ⁵	
Attenuation			Max. 60 dB	
Power repeatability (typical)	± 0.003 dB			
Power stability <sup>4</sup>	± 0.01 dB, 1 hour			
	Typical ± 0.03 dB, 24 hours			
Power linearity	± 0.1 dB			B in attenuation mode)
Power flatness versus wavelength	± 0.25 dB <sup>3</sup> , typical ± 0.1 dE	3	± 0.3 dB <sup>3</sup> , typica	al ± 0.15 dB
	Continuous sweep mode			
	At 5 nm/s	At 40 nm/s	At 80 nm/s	
Dynamic power reproducibility (typical)	± 0.005 dB	± 0.01 dB	± 0.015 dB	
Dynamic relative power flatness (typical)	± 0.01 dB	± 0.02 dB	± 0.04 dB	
Side-mode suppression ratio (typical)	≥ 60 dB (1520 nm to 1610 r	nm)		
Signal to source spontaneous emission	Output 1 (low SSE)		Output 2 (high p	
ratio <sup>2</sup>	≥ 70 dB/nm (1520 nm to 16		≥ 48 dB/nm (1520 nm to 1610 nm)	
	≥ 80 dB/0.1 nm (typical, 15	20 nm to	≥ 58 dB/0.1 nm (typical, 1520 nm to	
	1610 nm)		1610 nm)	
	≥ 66 dB/nm (typical, 1475 nm to 1625 nm)		≥ 43 dB/nm (1475 nm to 1625 nm)	
	≥ 60 dB/nm (typical) ⁵		≥ 37 dB/nm ⁵	
Signal to total source spontaneous	≥ 65 dB (1520 nm to 1610 r	nm)		1520 nm to 1610 nm)
emission ratio <sup>2</sup>	≥ 57 dB (typical) ⁵		∠ 00 0D (typicat,	
Relative intensity noise (RIN)	–145 dB/Hz (1520 nm to 16	610 nm)		
(0.1 to 6 GHz) (typ.) <sup>2</sup>				

1. Valid for one month and within a ± 4.4 K temperature range after automatic wavelength zeroing.

- 2. At maximum output power as specified per wavelength range.
- 3. Wavelength range 1455 nm to 1640 nm (81600B Option 201); 1440 nm to 1630 nm (81600B Option 200).
- 4. At constant temperature  $\pm$  1 K.
- 5. Wavelength range 1455 nm to 1640 nm (81600B Option 201); 1440 nm to 1640 nm (81600B Option 200).

81600B-201: v2.4 81600B-200: v2.3

## 81600B Option 160 Tunable Laser Source, 1495 nm to 1640 nm, Low SSE

Keysight 81600B Option 160	1/0E pm to 16/0 pm			
Wavelength range	1495 nm to 1640 nm			
Wavelength resolution	0.1 pm, 12.5 MHz at 1550 nm			
Mode-hop free tunability full	Full wavelength range; see	page 10 for conditio	ins to assure mode-hop	o free continuous sweeps
Maximum sweep speed	80 nm/s			
	Stepped mode	Continuous swee		
		At 5 nm/s	At 40 nm/s	At 80 nm/s
Absolute wavelength accuracy <sup>1</sup>	± 10 pm, typical ± 3.6 pm	± 4.0 pm	± 4.6 pm	± 6.1 pm
Relative wavelength accuracy <sup>1</sup>	± 5 pm, typical ± 2 pm	± 2.4 pm	± 2.8 pm	± 4.0 pm
Wavelength repeatability	± 0.8 pm, typical ± 0.5 pm	± 0.3 pm	± 0.4 pm	± 0.7 pm
Wavelength stability <sup>3</sup> (typical)	≤±1 pm, 24 hours			
Linewidth (typical), coherence control off	100 kHz			
Effective linewidth (typical), coherence control on	> 50 MHz (1510 nm to 1620	nm, at max. consta	nt output power)	
Maximum output power (continuous	Output 1 (low SSE)		Output 2 (high p	ower)
power during sweep)	≥ –2 dBm peak (typical)		≥ +7 dBm peak (t	
	≥ -4 dBm (1520 nm to 1610 nm)		≥ +5 dBm (1520 r	
	≥ -6 dBm (1510 nm to 1620 nm)		≥ +3 dBm (1510 r	
	≥ –7 dBm (1495 nm to1640	nm)	≥ –1 dBm (1495 r	nm to 1640 nm)
Attenuation			Max. 60 dB	
Power repeatability (typical)	± 0.003 dB			
Power stability <sup>3</sup>	± 0.01 dB, 1 hour			
	Typical ± 0.03 dB, 24 hours			
Power linearity	± 0.1 dB		· · · · · · · · · · · · · · · · · · ·	3 in attenuation mode)
Power flatness versus wavelength	± 0.25 dB, typical ± 0.1 dB (1495 nm to 1630 nm)		± 0.3 dB, typical	± 0.15 dB
	Continuous sweep mode			
	At 5 nm/s	At 40 nm/s	At 80 nm/s	
Dynamic power reproducibility (typical)	± 0.005 dB	± 0.01 dB	± 0.015 dB	
Dynamic relative power flatness (typical)	± 0.01 dB	± 0.02 dB	± 0.04 dB	
Side-mode suppression ratio (typical) <sup>2</sup>	≥ 40 dB (1520 nm to 1610 n	m)		
Signal to source spontaneous emission	Output 1 (low SSE)		Output 2 (high p	ower)
ratio <sup>2</sup>	≥ 64 dB/nm (1520 nm to1610 nm)		≥ 45 dB/nm (152	0 nm to 1610 nm)
	≥ 74 dB/0.1 nm		≥ 55 dB/0.1 nm	
	(typical, 1520 nm to 1610 nm)		(typical, 1520 nm	n to 1610 nm)
	≥ 62 dB/nm (typical, 1510 nm to 1620 nm)		≥ 42 dB/nm (1510	0 nm to 1620 nm)
	≥ 59 dB/nm (typical, 1495 r		≥ 37 dB/nm (149	5 nm to 1640 nm)
Signal to total source spontaneous	≥ 59 dB (1520 nm to 1610 n			
emission ratio <sup>2</sup>	≥ 56 dB (typical, 1495 nm to			/
Relative intensity noise (RIN) (0.1 to 6 GHz) (typical) <sup>2</sup>	–145 dB/Hz (1520 nm to 16			

1. Valid for one month and within a  $\pm$  4.4 K temperature range after automatic wavelength zeroing.

2. At maximum output power as specified per wavelength range.

## 81600B Option 150 Tunable Laser Source, 1450 nm to 1590 nm, Low SSE

Keysight 81600B Option 150				
Wavelength range	1450 nm to 1590 nm			
Wavelength resolution	Wavelength resolution 0.1 pm, 12.5 MHz at 1550 nm			
Mode-hop free tunability	Full wavelength range; see page 10 for conditions to assure mode-hop free continuous sweeps			o free continuous sweeps
Maximum sweep speed	80 nm/s			· · ·
· · ·	Stepped mode	Continuous sweep	mode (typical)	
	·	At 5 nm/s	At 40 nm/s	At 80 nm/s
Absolute wavelength accuracy <sup>1</sup>	± 10 pm, typical ± 3.6 pm	± 4.0 pm	± 4.6 pm	± 6.1 pm
Relative wavelength accuracy <sup>1</sup>	± 5 pm, typical ± 2 pm	± 2.4 pm	± 2.8 pm	± 4.0 pm
Wavelength repeatability	± 0.8 pm, typical ± 0.5 pm	± 0.3 pm	± 0.4 pm	± 0.7 pm
Wavelength stability <sup>3</sup> (typical)	≤ ± 1 pm, 24 hours	·	·	·
Linewidth (typical), coherence	100 kHz			
control off				
Effective linewidth (typical),	> 50 MHz (1480 nm to 1580	) nm, at max. constar	it output power)	
coherence control on				
Maximum output power (continuous	Output 1 (low SSE)		Output 2 (high po	wer)
power during sweep)	≥ –1 dBm peak (typical)		≥ +7 dBm peak (ty	
	≥ -3 dBm (1520 nm to 1570 nm)		≥ +5 dBm (1520 ni	
	≥ -6 dBm (1480 nm to 1580 nm)		≥ +4 dBm (1480 n	m to 1580 nm)
	≥ -7 dBm (1450 nm to 1590		≥ –1 dBm (1450 nr	n to 1590 nm)
Attenuation	· · ·		Max 60 dB	· · ·
Power repeatability (typical)	± 0.003 dB			
Power stability <sup>3</sup>	± 0.01 dB, 1 hour			
	Typical ± 0.03 dB, 24 hours			
Power linearity	± 0.1 dB		± 0.1 dB (± 0.3 dB	in attenuation mode)
Power flatness versus wavelength	± 0.2 dB, typical ± 0.1 dB		± 0.3 dB, typical ±	
	Continuous sweep mode			
	At 5 nm/s	At 40 nm/s	At 80 nm/s	
Dynamic power reproducibility	± 0.005 dB	± 0.01 dB	± 0.015 dB	
(typical)				
Dynamic relative power flatness	± 0.01 dB	± 0.02 dB	± 0.04 dB	
(typical)				
Side-mode suppression ratio	≥ 40 dB (1480 nm to 1580 r	ım)		
(typical) <sup>2</sup>	·			
Signal to source spontaneous	Output 1 (low SSE)		Output 2 (high po	ower)
emission ratio <sup>2</sup>	≥ 65 dB/nm (1520 nm to 15	70 nm)	≥ 45 dB/nm (1520	
	≥ 75 dB/0.1 nm (typical, 1520 nm to 1570 nm)		≥ 55 dB/0.1 nm (typical, 1520 nm to 1570 nm	
	≥ 61 dB/nm (typical, 1480 r		≥ 42 dB/nm (1480	
	≥ 59 dB/nm (typical, 1450 r		≥ 37 dB/nm (1450	
Signal to total source spontaneous	≥ 60 dB (1520 nm to 1570 r			·
emission ratio <sup>2</sup>	≥ 50 dB (typical, 1450 nm t		— ≥ 30 dB (typical, 1	520 nm to 1570 nm)
Relative intensity noise (RIN)	–145 dB/Hz (1480 nm to 15			
$(0.1 \text{ to } 6 \text{ GHz}) (\text{typical})^2$		· · · · · · · ·		

### . .

1. Valid for one month and within a ± 4.4 K temperature range after automatic wavelength zeroing.

2. At maximum output power as specified per wavelength range.

## 81600B Option 140 Tunable Laser Source, 1370 nm to 1495 nm, Low SSE

Keysight 81600B Option 140 Wavelength range	1370 nm to 1495 nm				
Wavelength resolution	0.1 pm, 15 MHz at 1450 nm				
Mode-hop free tunability full	Full wavelength range; see page 10 for conditions to assure mode-hop free continue			ee continuous sweeps	
Maximum sweep speed	80 nm/s (1372 nm to 1495 nr	,	. ()		
	Stepped mode		veep mode (typical)		
		At 5 nm/s	At 40 nm/s	At 80 nm/s	
Absolute wavelength accuracy <sup>1</sup>	± 10 pm, typical ± 3.6 pm	± 4.0 pm	± 4.6 pm	± 6.1 pm	
Relative wavelength accuracy <sup>1</sup>	± 5 pm, typical ± 2 pm	± 2.4 pm	± 2.8 pm	± 4.0 pm	
Wavelength repeatability	± 0.8 pm, typical ± 0.5 pm	± 0.3 pm	± 0.4 pm	± 0.7 pm	
Wavelength stability <sup>4</sup> (typical)	≤ ± 1 pm, 24 hours				
Linewidth (typical), coherence control off	100 kHz				
Effective linewidth (typical), coherence control on	> 50 MHz (1430 nm to 1480 r	nm, at max. constant	output power)		
Maximum output power	Output 1 (low SSE)		Output 2 (high	power)	
(continuous power during sweep)	≥ –4.5 dBm peak (typical)		≥ +5.5 dBm peak	(typical)	
	≥ –5 dBm (1430 nm to 1480 i	nm)	≥ +5 dBm (1430 n	nm to 1480 nm)	
	≥ -7 dBm (1420 nm to 1480 nm)		≥ +3 dBm (1420 n	m to 1480 nm)	
	≥ -13 dBm (1370 nm to 1495 nm)		≥ -3 dBm (1370 nm to 1495 nm)		
Attenuation			Max 60 dB		
Power repeatability (typical)	± 0.003 dB				
Power stability <sup>4</sup>	± 0.01 dB, 1 hour (1420 nm to 1495 nm)				
	Typical ± 0.01 dB, 1 hour (1370 nm to 1420 nm)				
	Typical ± 0.03 dB, 24 hours				
Power linearity	± 0.1 dB (1420 nm to 1495 nr	n)	± 0.3 dB (1420 nm	n to 1495 nm)	
	Typical ± 0.1 dB (1370 nm to	1420 nm)	Typical ± 0.3 dB (*	1370 nm to 1420 nm)	
Power flatness versus wavelength	± 0.2 dB		± 0.3 dB		
	Typical ± 0.1 dB (1420 nm to 1495 nm)		Typical ± 0.2 dB (*	1420 nm to 1495 nm)	
	Typical ± 0.2 dB (1370 nm to	1420 nm)	Typical ± 0.3 dB (	Typical ± 0.3 dB (1370 nm to 1420 nm)	
	Continuous sweep mode	3			
	At 5 nm/s	At 40 nm/s	At 80 nm/s		
Dynamic power reproducibility (typical)	± 0.005 dB	± 0.01 dB	± 0.015 dB		
Dynamic relative power flatness (typical)	± 0.01 dB	± 0.015 dB	± 0.03 dB		
Side-mode suppression ratio (typical) <sup>2</sup>	≥ 40 dB (1430 nm to 1480 nn	n)			
Signal to source spontaneous emission	Output 1 (low SSE)		Output 2 (high	power)	
ratio <sup>2</sup>	<ul> <li>2 63 dB/nm (1430 nm to 148</li> <li>2 73 dB/0.1 nm (typical, 1430</li> <li>2 61 dB/nm (1420 nm to 1480</li> <li>2 55 dB/nm (typical, 1370 nm</li> </ul>	0 nm to 1480 nm) 0 nm)	≥ 42 dB/nm (1430 ≥ 52 dB/0.1 nm (t ≥ 40 dB/nm (1420	) nm to 1480 nm) ypical, 1430 nm to 1480 nm)	
Signal to total source spontaneous emis-	≥ 60 dB (1430 nm to 1480 nm)		≥ 28 dB (typical, 1	1430 nm to 1480 nm)	
sion ratio <sup>2</sup>	≥ 58 dB (1420 nm to 1480 nm)				
	≥ 53 dB (typical, 1370 nm to	1495 nm)			
Relative intensity noise (RIN) (0.1 to 6 GHz) (typical) <sup>2</sup>	–145 dB/Hz (1430 nm to 148	0 nm)			

1. Valid for one month and within a  $\pm$  4.4 K temperature range after automatic wavelength zeroing.

2. At maximum output power as specified per wavelength range.

3. Valid for absolute humidity of 11.5 g/m3 (For example, equivalent to 50% relative humidity at 25 °C).

### 81600B Option 130 Tunable Laser Source, 1260 nm to 1375 nm, Low SSE

Keysight 81600B Option 130					
Wavelength range	1260 nm to 1375 nm				
Wavelength resolution	0.1 pm, 17.7 MHz at 1300 nm				
Mode-hop free tunability	Full wavelength range; see page 10 for conditions to assure mode-hop free continuous sweeps				
Maximum sweep speed	80 nm/s				
	Stepped mode Continuous sweep mode (typical)				
		At 5 nm/s	At 40 nm/s	At 80 nm/s	
Absolute wavelength accuracy <sup>1</sup>	± 10 pm, typical ± 3.6 pm	± 4.0 pm	± 4.6 pm	± 6.1 pm	
Relative wavelength accuracy <sup>1</sup>	± 5 pm, typical ± 2 pm	± 2.4 pm	± 2.8 pm	± 4.0 pm	
Wavelength repeatability	± 0.8 pm, typical ± 0.5 pm	± 0.3 pm	± 0.4 pm	± 0.7 pm	
Wavelength stability <sup>4</sup> (typical)	≤ ±1 pm, 24 hours				
Linewidth (typical), coherence control off	100 kHz				
Effective linewidth (typical), coherence control on	> 50 MHz (1270 nm to 1350 )	nm, at max. constant (	output power)		
Maximum output power (continuous power	Output 1 (low SSE)		Output 2 (high po	ower)	
during sweep)	≥ –4 dBm peak (typical)		≥ +5 dBm peak (ty	pical)	
	≥ -6 dBm (1290 nm to 1370 nm)		≥ +4 dBm (1290 n	m to 1370 nm)	
	≥ -9 dBm (1270 nm to 1375 nm)		≥ +1 dBm (1270 nr	≥ +1 dBm (1270 nm to 1375 nm)	
	≥ –13 dBm (1260 nm to 1375 nm)		≥ -3 dBm (1260 nm to 1375 nm)		
Attenuation			Max 60 dB		
Power repeatability (typical)	± 0.003 dB				
Power stability <sup>4</sup>	± 0.01 dB, 1 hour (1260 nm to 1350 nm)				
	Typical ± 0.01 dB, 1 hour (1350 nm to 1375 nm)				
	Typical ± 0.03 dB, 24 hours				
Power linearity	± 0.1 dB (1260 nm to 1350 nm	m)	±0.3 dB (1260 nm	to 1350 nm)	
	Typical ± 0.1 dB (1350 nm to	1375 nm)	Typical ± 0.3 dB (1	350 nm to 1375 nm)	
Power flatness versus wavelength	± 0.2 dB		± 0.3 dB		
	Typical ± 0.1 dB (1260 nm to	1350 nm)	Typical ± 0.15 dB (1260 nm to 1350 nm)		
	Typical ± 0.2 dB (1350 nm to 1375 nm)		Typical ± 0.3 dB (1	350 nm to 1375 nm)	
	Continuous sweep mode <sup>3</sup>				
	At 5 nm/s	At 40 nm/s	At 80 nm/s		
Dynamic power reproducibility (typical)	± 0.005 dB	± 0.01 dB	± 0.015 dB		
Dynamic relative power flatness (typical)	± 0.01 dB	± 0.02 dB	± 0.04 dB		
Side-mode suppression ratio (typical) <sup>2</sup>	≥ 40 dB (1290 nm to 1370 nr	n)			
Signal to source spontaneous emission ratio	Output 1 (low SSE)		Output 2 (high po	ower)	
(typical) <sup>2</sup>	≥ 63 dB/nm (1290 nm to 137	'0 nm)	≥ 42 dB/nm (1290	nm to 1370 nm)	
	≥ 61 dB/nm (1270 nm to 1375 nm)		≥ 40 dB/nm (1270	nm to 1375 nm)	
	≥ 55 dB/nm (1260 nm to 137	5 nm)	≥ 35 dB/nm (1260	nm to 1375 nm)	
Signal to total source spontaneous emission	≥ 58 dB (1290 nm to 1370 nm)		≥ 26 dB (1290 nm	to 1370 nm)	
ratio (typical) <sup>2</sup>	≥ 56 dB (1270 nm to 1375 nn	n)			
	≥ 51 dB (1260 nm to 1375 nn	n)			
Relative intensity noise (RIN) (0.1 to 6 GHz) (typical) <sup>2</sup>	–140 dB/Hz (1270 nm to 137	5 nm)			

1. Valid for one month and within a  $\pm$  4.4 K temperature range after automatic wavelength zeroing.

2. At maximum output power as specified per wavelength range.

3. Valid for absolute humidity of 11.5 g/m3 (For example, equivalent to 50% relative humidity at 25 °C).

### 81600B Option 142 Tunable Laser Source, 1370 nm to 1495 nm, High Power

Keysight 81600B Option 142					
Wavelength range	1370 nm to 1495 nm				
Wavelength resolution	0.1 pm, 15 MHz at 1450 nm				
Mode-hop free tunability	Full wavelength range; see page 10 for conditions to assure mode-hop free continuous sweeps			continuous sweeps	
Maximum sweep speed	80 nm/s (1372 nm to 1495 n	m)			
	Stepped mode Continuous sweep mode (typical)				
		At 5 nm/s	At 40 nm/s	At 80 nm/s	
Absolute wavelength accuracy <sup>1</sup>	± 10 pm, typical ± 3.6 pm	± 4.0pm	± 4.6 pm	± 6.1 pm	
Relative wavelength accuracy <sup>1</sup>	± 5 pm, typical ± 2 pm	± 2.4 pm	± 2.8 pm	± 4.0 pm	
Wavelength repeatability	± 0.8 pm, typical ± 0.5 pm	± 0.3 pm	± 0.4 pm	± 0.7 pm	
Wavelength stability 4 (typical)	≤ ± 1 pm, 24 hours				
Linewidth (typical), coherence control off	100 kHz				
Effective linewidth (typical), coherence control on	> 50 MHz (1430 nm to 1480	nm, at max. constant	output power)		
Maximum output power (continuous power	≥ +8.5 dBm peak (typical)				
during sweep)	≥ +7.5 dBm (1430 nm to 148	0 nm)			
	≥ +5 dBm (1420 nm to 1480	nm)			
With option 003	≥ 0 dBm (1370 nm to 1495 n	m)			
	Reduced by 1.5 dB				
Power repeatability (typical)	± 0.003 dB				
Power stability <sup>4</sup>	± 0.01 dB, 1 hour (1420 nm to 1495 nm)				
	Typical ± 0.01 dB, 1 hour (1370 nm to 1420 nm)				
	Typical ± 0.03 dB, 24 hours				
Power linearity	± 0.1 dB (1420 nm to 1495 n	m)			
With antion 000	Typical ± 0.1 dB (1370 nm to 1420 nm)				
With option 003	Add ± 0.2 dB				
Power flatness versus wavelength	± 0.2 dB				
	Typical ± 0.1 dB (1420 nm to	1495 nm)			
With option 003	Typical ± 0.2 dB (1370 nm to	1420 nm)			
	Add ± 0.1 dB				
	Continuous sweep mode	<b>e</b> <sup>3</sup>			
	At 5 nm/s	At 40 nm/s	At 80 nm/s		
Dynamic power reproducibility (typical)	± 0.005 dB	± 0.01 dB	± 0.015 dB		
Dynamic relative power flatness (typical)	± 0.01 dB	± 0.015 dB	± 0.03 dB		
Side-mode suppression ratio (typical) <sup>2</sup>	≥ 40 dB (1430 nm to 1480 n	m)			
Signal to source spontaneous emission ratio <sup>2</sup>	≥ 42 dB/nm (1430 nm to 1480 nm)				
	≥ 52 dB/0.1 nm (typical, 1430 nm to 1480 nm)				
	≥ 40 dB/nm (1420 nm to 148	30 nm)			
	≥ 35 dB/nm (typical, 1370 nr	m to 1495 nm)			
Signal to total source spontaneous emission ratio (typical) <sup>2</sup>	≥ 28 dB (1430 nm to 1480 ni	m)			
Relative intensity noise (RIN) (0.1 to 6 GHz) (typical) <sup>2</sup>	–145 dB/Hz (1430 nm to 148	30 nm)			

1. Valid for one month and within a ± 4.4 K temperature range after automatic wavelength zeroing.

2. At maximum output power as specified per wavelength range.

3. Valid for absolute humidity of 11.5 g/m3 (For example, equivalent to 50% relative humidity at 25  $^{\circ}$ C).

### 81600B Option 132 Tunable Laser Source, 1260 nm to 1375 nm, High Power

Keysight 81600B Option 132					
Wavelength range	1260 nm to 1375 nm				
Wavelength resolution	0.1 pm, 17.7 MHz at 1300 nm				
Mode-hop free tunability	Full wavelength range; see page 10 for conditions to assure mode-hop free continuous sweeps		p free continuous		
Maximum sweep speed	80 nm/s				
	Stepped mode	Continuous sw	eep mode (typical)		
		At 5 nm/s	At 40 nm/s	At 80 nm/s	
Absolute wavelength accuracy <sup>1</sup>	± 10 pm, typical ± 3.6 pm	± 4.0 pm	± 4.6 pm	± 6.1 pm	
Relative wavelength accuracy <sup>1</sup>	± 5 pm, typical ± 2 pm	± 2.4 pm	± 2.8 pm	± 4.0 pm	
Wavelength repeatability	± 0.8 pm, typical ± 0.5 pm	± 0.3 pm	± 0.4 pm	± 0.7 pm	
Wavelength stability <sup>2</sup> (typical)	≤±1 pm, 24 hours				
Linewidth (typical), coherence control off	100 kHz				
Effective linewidth (typical), coherence control on	> 50 MHz (1270 nm to 1350	) nm, at max. cons	tant output power)		
Maximum output power	≥ +9 dBm peak (typical)				
(continuous power during sweep)	≥ +7 dBm (1290 nm to 1370 nm)				
	≥ +3 dBm (1270 nm to 1375 nm)				
	≥ 0 dBm (1260 nm to 1375 nm)				
Power repeatability (typical)	± 0.003 dB				
Power stability <sup>4</sup>	± 0.01 dB, 1 hour (1260 nm to 1350 nm)				
	Typical ± 0.01 dB, 1 hour (1350 nm to 1375 nm)				
	Typical ± 0.03 dB, 24 hours				
Power linearity	± 0.1 dB (1260 nm to 1350 r	nm)			
	Typical ± 0.1 dB (1350 nm to	o 1375 nm)			
Power flatness versus wavelength	± 0.2 dB				
	Typical ± 0.1 dB (1260 nm to 1350 nm)				
	Typical ± 0.2 dB (1350 nm to 1375 nm)				
	Continuous sweep mode <sup>3</sup>				
	At 5 nm/s	At 40 nm/s	At 80 nm/s		
Dynamic power reproducibility (typical)	± 0.005 dB	± 0.01 dB	± 0.015 dB		
Dynamic relative power flatness (typical)	± 0.01 dB	± 0.015 dB	± 0.03 dB		
Side-mode suppression ratio (typical) <sup>2</sup>	≥ 40 dB (1270 nm to 1375 n	m)			
Signal to source spontaneous emission	≥ 45 dB/nm (1290 nm to 13	70 nm)			
ratio <sup>2</sup>	≥ 55 dB/0.1 nm (typical, 1290 nm to 1370 nm)				
	≥ 40 dB/nm (1270 nm to 1375 nm)				
	≥ 35 dB/nm (typical, 1260 r	ım to 1375 nm)			
Signal to total source spontaneous emis- sion ratio (typical) <sup>2</sup>	≥ 28 dB (1290 nm to 1370 n	im)			
Relative intensity noise (RIN) (0.1 to 6 GHz) (typical) <sup>2</sup>	–145 dB/Hz (1270 nm to 13	75 nm)			

1. Valid for one month and within a  $\pm$  4.4 K temperature range after automatic wavelength zeroing.

2. At maximum output power as specified per wavelength range.

3. Valid for absolute humidity of 11.5 g/m3 (For example, equivalent to 50% relative humidity at 25 °C).

4. At constant temperature  $\pm$  1 K.

81600B-132: v2.4

## Conditions

Storage temperature	-40 °C to +70 °C
Operating temperature	+10 °C to +35 °C
Humidity	< 80% R.H. at +10 °C to +35 °C, non-condensing
Specifications apply for wavelengths	not equal to any water absorption line.
Warm-up time	1 h; immediate operation after boot up
Output power	
Specifications are valid at the following	ng output power levels:
Options 201, 200, 160 and 150	$\ge$ −7 dBm (for Output 1); $\ge$ −1 dBm (for Output 2, −60 dB in attenuation mode)
81600B Option 140 and 130	≥ –13 dBm (for Output 1); ≥ –3 dBm (for Output 2, –60 dB in attenuation mode)
81600B Option 142	$\ge$ –3 dBm; $\ge$ –4.5 dBm (with Option 003: –60 dB in attenuation mode)
81600B Option 132	≥ 0 dBm
Continuous sweep mode	
Specifications are valid for mode-hop	o free sweeping. Maximum 50 nm at constant output power levels as follows:
81600B Option 200, 201	1475 nm to 1620 nm; $\ge -2$ dBm (for Output 1); $\ge +4$ dBm (for Output 2)
81600B Option 160	1510 nm to 1620 nm; $\ge -6$ dBm (for Output 1); $\ge +3$ dBm (for Output 2)
81600B Option 150	1520 nm to 1570 nm; $\ge -6$ dBm (for Output 1); $\ge +3$ dBm (for Output 2)
81600B Option 140	1430 nm to 1480 nm; $\ge -9$ dBm (for Output 1); $\ge 0$ dBm (for Output 2)
81600B Option 130	1300 nm to 1350 nm; $\ge -9$ dBm (for Output 1); $\ge +1$ dBm (for Output 2)
81600B Option 142	1430 nm to 1480 nm; ≥ –3 dBm; ≥ +1.5 dBm (with Option 003)
81600B Option 132	1300 nm to 1350 nm; ≥ +3 dBm
Operating temperature within	+20 °C and +35 °C

## General Specifications and Supplementary Characteristics

Supplementary performance char	racteristics
Internal digital modulation	
	50% duty cycle, 200 Hz to 300 kHz
	Displayed wavelength represents average wavelength.
Modulation output	TTL reference signal
External digital modulation	
	> 45% duty cycle, delay time
	< 300 ns, 200 Hz to 1 MHz
	Displayed wavelength represents average wavelength.
Modulation input	TTL signal
External analog modulation	
	$\ge \pm 15\%$ modulation depth, 5 kHz to 20 MHz
Modulation input	5 Vp-p
External wavelength locking	
	> ± 70 pm at 10 Hz
	> ± 7 pm at 100 Hz
Modulation input	±5V
Coherence control	
	s with 2 m long patch cords and connectors with 14 dB return loss, the effective linewidth results in a d d B over 1 minute by significantly reducing interference effects in the test setup.
General Output isolation (typical)	
output isolation (typical)	50 dB
Return loss (typical)	
Notarii tooo (typiout)	60 dB (Option 072)
	40 dB (Option 071)
Polarization maintaining fiber (O	
Fiber type	Panda
Orientation	TE mode in slow axis, in line with connector key
Polarization extinction ratio	
	16 dB typical
	14 dB typical (Option 200, 201)
Recommended re-calibration per	riod
	2 years

#### -----.

### Ordering Information

### Lightwave solution mainframe 8164B



### Tunable laser module: 81600B

One of the following is required:	
Option 200	All-band tunable laser source 1440 nm to 1640 nm, low SSE
Option 201	All-band tunable laser source 1455 nm to 1640 nm, low SSE
Option 160	Tunable laser source 1495 nm to 1640 nm, low SSE
Option 150	Tunable laser source 1450 nm to 1590 nm, low SSE
Option 140	Tunable laser source 1370 nm to 1495 nm, low SSE
Option 130	Tunable laser source 1260 nm to 1375 nm, low SSE
Option 142	Tunable laser source 1370 nm to 1495 nm, high power
Option 132	Tunable laser source 1260 nm to 1375 nm, high power
Connector option	
One of the following is required:	
Option 071	PMF, straight contact output connector
Option 072 (recommended)	PMF, angled contact output connector
Other option	
Option 003	Built-in optical attenuator, 60 dB attenuation (for Option 142)
Connector interface	
One Keysight 81000xI-series connector inter	face is required for Options 142 and 132
Two Keysight 81000xI-series connector inter	faces are required for Options 201, 200, 160, 150, 140 and 130
Custom-made TLS	
A 1650 nm Tunable Laser Source is available	on request. Please contact your local Keysight Sales Office.

Laser safety information

All laser sources specified by this data sheet are classified as Class 1M according to IEC 60825-1 (2007).

All laser sources comply with 21 CFR 1040.10 except for deviations pursuant to Laser Notice No. 50, dated 2007, June 24.

INVISIBLE LASER RADIATION DO NOT VIEW DIRECTLY WITH OPTICAL INSTRUMENTS CLASS 1M LASER PRODUCT (IEC 60825-1:2007)

#### myKeysight

**myKeysight** 

### www.keysight.com/find/mykeysight

A personalized view into the information most relevant to you.

#### www.axiestandard.org



### www.lxistandard.org

Three-Year Warranty

LAN eXtensions for Instruments puts the power of Ethernet and the Web inside your test systems. Keysight is a founding member of the LXI consortium.



#### www.keysight.com/find/ThreeYearWarranty

Keysight's commitment to superior product quality and lower total cost of ownership. The only test and measurement company with three-year warranty standard on all instruments, worldwide.



#### www.keysight.com/find/AssurancePlans

Keysight Assurance Plans

Up to five years of protection and no budgetary surprises to ensure your instruments are operating to specification so you can rely on accurate measurements.



#### www.keysight.com/go/quality

Keysight Technologies, Inc. DEKRA Certified ISO 9001:2008 Quality Management System

### Keysight Channel Partners

#### www.keysight.com/find/channelpartners

Get the best of both worlds: Keysight's measurement expertise and product breadth, combined with channel partner convenience.

www.keysight.com/find/tls

For more information on Keysight Technologies' products, applications or services, please contact your local Keysight office. The complete list is available at: www.keysight.com/find/contactus

#### Americas

Canada	(877) 894 4414
Brazil	55 11 3351 7010
Mexico	001 800 254 2440
United States	(800) 829 4444

#### Asia Pacific

Australia	1 800 629 485
China	800 810 0189
Hong Kong	800 938 693
India	1 800 112 929
Japan	0120 (421) 345
Korea	080 769 0800
Malaysia	1 800 888 848
Singapore	1 800 375 8100
Taiwan	0800 047 866
Other AP Countries	(65) 6375 8100

#### Europe & Middle East

Austria	0800 001122
Belgium	0800 58580
Finland	0800 523252
France	0805 980333
Germany	0800 6270999
Ireland	1800 832700
Israel	1 809 343051
Italy	800 599100
Luxembourg	+32 800 58580
Netherlands	0800 0233200
Russia	8800 5009286
Spain	800 000154
Sweden	0200 882255
Switzerland	0800 805353
	Opt. 1 (DE)
	Opt. 2 (FR)
	Opt. 3 (IT)
United Kingdom	0800 0260637

For other unlisted countries: www.keysight.com/find/contactus (BP-09-04-14)



This information is subject to change without notice. © Keysight Technologies, 2013 - 2014 Published in USA, August 3, 2014 5989-7321EN www.keysight.com